

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination YAMADA ET AL.	
			Examiner SCOTT R. WILSON	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,107,648	08-2000	Shakuda et al.	257/103
*	B	US-4,100,014	07-1978	Kuhn-Kuhnenfeld et al.	438/745
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	IDS Reference, Huang et al., "Twofold efficiency improvement in high performance AlGaN/P light-emitting diodes in the 555-620 nm spectral region using a thick GaP window layer", Applied Physics Letters - August 31, 1992 - Volume 61, Issue 9, pp. 1045-1047
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.